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» **Key**

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

Modify Search

(((phase noise) and (spectrum analyzer))<in>metadata)

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Display Format: ◉ Citation   ○ Citation & Abstract

Select   **Article Information**

☐   1. **Measuring phase noise at K-band**
Key-Bolotin, J.A.; Chut-San Tsang;
Aerospace Conference, 1999. Proceedings. 1999 IEEE
Volume 5, 6-13 March 1999 Page(s):193 - 209 vol.5

AbstractPlus | Full Text: PDF(868 KB)   **IEEE CNF**

☐   2. **Phase noise measurement of free-running VCO using spectrum analyzer**
Chung Ming Yuen; Kim Fung Tsang;
Radio and Wireless Conference, 2004 IEEE
19-22 Sept. 2004 Page(s):443 - 446

AbstractPlus | Full Text: PDF(535 KB)   **IEEE CNF**

☐   3. **How to use a spectrum analyzer to measure phase noise of digital signal generat**
Zhan Zhiqiang;
Radio Science Conference, 2004. Proceedings. 2004 Asia-Pacific
24-27 Aug. 2004 Page(s):128 - 130

AbstractPlus | Full Text: PDF(1780 KB)   **IEEE CNF**

☐   4. **Using digital data processing to speed up radar phase noise measurements**
Guhse, D.; Luster, B.; Prcic, M.;
AUTOTESTCON '94. IEEE Systems Readiness Technology Conference. 'Cost Effectiv
Next Century', Conference Proceedings.
20-22 Sept. 1994 Page(s):205 - 210

AbstractPlus | Full Text: PDF(600 KB)   **IEEE CNF**

☐   5. **Phase noise measurement of free-running microwave oscillators at 5.8 GHz usin subharmonic injection locking**
Kim Fung Tsang; Chung Ming Yuen;
Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Gu Letters]
Volume 15, Issue 4, April 2005 Page(s):217 - 219

AbstractPlus | Full Text: PDF(128 KB)   **IEEE JNL**

☐   6. **A frequency conversion scheme for an advanced portable microwave spectrum ɨ**
Hill, T.; Lockwood, L.;
Microwave Symposium Digest, 1990., IEEE MTT-S International
8-10 May 1990 Page(s):447 - 450 vol.1

AbstractPlus | Full Text: PDF(200 KB)   **IEEE CNF**

7. **The influence of transistor nonlinearities on noise properties**
Sungjae Lee; Webb, K.J.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 53, Issue 4, April 2005 Page(s):1314 - 1321
AbstractPlus | Full Text: PDF(432 KB)   **IEEE JNL**

8. **MOSFET 1/f noise measurement under switched bias conditions**
Zhang, C.W.; Louie, M.Y.; Forbes, L.;
Microelectronics and Electron Devices, 2004 IEEE Workshop on
2004 Page(s):79 - 81
AbstractPlus | Full Text: PDF(1435 KB)   **IEEE CNF**

9. **Automated phase noise measurement of Ku-band MMIC VCO on-wafer**
Yang, J.M.; Yang, D.C.; Cheng, P.G.; Dickson, J.M.;
Microwave Symposium Digest, 1999 IEEE MTT-S International
Volume 4, 13-19 June 1999 Page(s):1763 - 1766 vol.4
AbstractPlus | Full Text: PDF(164 KB)   **IEEE CNF**

10. **Phase noise measurements of a double-locked laser diode**
Simpson, T.B.; Doft, F.; Shin, D.S.; Yu, P.K.L.;
Lasers and Electro-Optics Society, 2001. LEOS 2001. The 14th Annual Meeting of the
Volume 1, 12-13 Nov. 2001 Page(s):117 - 118 vol.1
AbstractPlus | Full Text: PDF(155 KB)   **IEEE CNF**

11. **Phase noise in surface-acoustic-wave filters and resonators**
Baer, R.L.;
Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on
Volume 35, Issue 3, May 1988 Page(s):421 - 425
AbstractPlus | Full Text: PDF(372 KB)   **IEEE JNL**

12. **Noise characterisation of mode-locked laser sources using high-speed InGaAs p**
Finch, A.; Burns, D.; Zhu, X.N.; Sleat, W.E.; Sibbett, W.;
Applications of Ultrashort Pulses for Optoelectronics, IEE Colloquium on
26 May 1989 Page(s):8/1 - 8/4
AbstractPlus | Full Text: PDF(252 KB)   **IEE CNF**

13. **YBCO shielded LaAlO/sub 3/ dielectric resonators for stable oscillators**
Klein, N.; Tellmann, N.; Dahne, T.; Scholen, A.; Schulz, H.; Hofer, G.; Kratz, H.;
Applied Superconductivity, IEEE Transactions on
Volume 5, Issue 2, Jun 1995 Page(s):2663 - 2666
AbstractPlus | Full Text: PDF(312 KB)   **IEEE JNL**

14. **A 2.5-GHz eight-phase VCO in SiGe BiCMOS technology**
Herzel, F.; Winkler, W.;
Circuits and Systems II: Express Briefs, IEEE Transactions on [see also Circuits and S
and Digital Signal Processing, IEEE Transactions on]
Volume 52, Issue 3, March 2005 Page(s):140 - 144
AbstractPlus | Full Text: PDF(224 KB)   **IEEE JNL**

15. **Increasing dynamic range of practical microwave spectrum analysis by reducing compensating system noise**
Lipovac, V.; Honisch, W.;
Microwave and Optoelectronics Conference, 2003. IMOC 2003. Proceedings of the 20
MTT-S International
Volume 2, 20-23 Sept. 2003 Page(s):1069 - 1073 vol.2

AbstractPlus | Full Text: PDF(338 KB)   **IEEE CNF**

☐ 16. **The influence of transistor nonlinearities on intrinsic noise**
Sungjae Lee; Webb, K.J.; Eastman, L.F.;
Microwave Symposium Digest, 2004 IEEE MTT-S International
Volume 3, 6-11 June 2004 Page(s):1867 - 1870 Vol.3

AbstractPlus | Full Text: PDF(490 KB)   **IEEE CNF**

☐ 17. **Extending the range for precision AM noise measurements**
Nelson, C.W.; Walls, F.L.; Boggs, C.K.;
Frequency Control Symposium, 1996. 50th., Proceedings of the 1996 IEEE Internation
5-7 June 1996 Page(s):854 - 857

AbstractPlus | Full Text: PDF(484 KB)   **IEEE CNF**

☐ 18. **Noise in mixers, oscillators, samplers, and logic an introduction to cyclostationa**
Phillips, J.; Kundert, K.;
Custom Integrated Circuits Conference, 2000. CICC. Proceedings of the IEEE 2000
21-24 May 2000 Page(s):431 - 438

AbstractPlus | Full Text: PDF(768 KB)   **IEEE CNF**

☐ 19. **Automated Spectral Analysis of Microwave Oscillator Noise**
Ashley, J.R.; Barley, T.A., Jr.; Rast, G.J.;
Microwave Symposium Digest, MTT-S International
Volume 76, Issue 1, Jun 1976 Page(s):227 - 229

AbstractPlus | Full Text: PDF(504 KB)   **IEEE CNF**

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	290	(spectrum adj2 analyzer) and (phase adj2 noise)	USPAT	OR	ON	2005/06/28 11:08
L5	958	model same phase same noise	USPAT	OR	ON	2005/06/28 11:04
L6	25	4 and 5	USPAT	OR	ON	2005/06/28 11:05
L7	0	("6621277").URPN.	USPAT	OR	ON	2005/06/28 11:08
L8	68	. (spectrum adj2 analyzer) same (phase adj2 noise)	USPAT	OR	ON	2005/06/28 11:11
L9	4	(spectrum adj2 analyzer) and (phase adj2 noise adj2 model)	USPAT	OR	ON	2005/06/28 11:25
L10	9	internal adj2 phase adj2 noise	USPAT	OR	ON	2005/06/28 11:27
L11	97	phase adj2 noise adj2 cancel$5	USPAT	OR	ON	2005/06/28 11:28
L12	6	11 and (spectrum adj2 analyzer)	USPAT	OR	ON	2005/06/28 11:27
L13	0	(phase adj2 noise adj2 cancel$5) same internal	USPAT	OR	ON	2005/06/28 11:28
L14	75	(phase same noise same cancel$7) same internal	USPAT	OR	ON	2005/06/28 11:33
L15	6278	vna or (spectrum adj2 analyzer)	USPAT	OR	ON	2005/06/28 11:33
L16	4933	phase adj2 noise	USPAT	OR	ON	2005/06/28 11:33
L17	292	15 and 16	USPAT	OR	ON	2005/06/28 11:33
L18	4	17 and (internal same cancel$7)	USPAT	OR	ON	2005/06/28 11:33
L19	6	("5172064").URPN.	USPAT	OR	ON	2005/06/28 11:46
L20	10	(sideband adj2 noise) same cancel$5	USPAT	OR	ON	2005/06/28 12:31
L21	45	internal same (noise or jitter) same spectrum same analyzer	USPAT	OR	ON	2005/06/28 12:35
L22	83	phase same noise same measurement same spectrum same analyzer	USPAT	OR	ON	2005/06/28 12:40
L23	20290	"702"/$.ccls.	USPAT	OR	ON	2005/06/28 14:36
L24	123	23 and (phase adj2 noise)	USPAT	OR	ON	2005/06/28 12:51
L25	1	"6730484".pn.	USPAT	OR	ON	2005/06/28 12:52
L26	1	"6370484".pn.	USPAT	OR	ON	2005/06/28 12:53
L27	1	"6335615".pn.	USPAT	OR	ON	2005/06/28 13:04
L28	2	("5337014" or "6313619").pn.	USPAT	OR	ON	2005/06/28 13:04
L29	659	702/111,106,107,69,72.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37
L30	914	331/18,19,44.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37
L31	1056	324/613,614,615,617,620,624, 622,76.19,76.22.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37

L32	1032	375/224,226,227.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37
L33	3555	29 or 30 or 31 or 32	US-PGPUB; USPAT	OR	ON	2005/06/28 14:37

Most Frequently Occurring Classifications of Patents Returned
From A Search of 10807205 on June 28, 2005

Original Classifications
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7   324/613
2   324/76.27
2   331/2
2   342/135
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Cross-Reference Classifications
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4   324/76.23
3   324/76.27
3   331/25
3   342/145
2   324/622
2   324/76.17
2   324/76.26
2   324/76.29
2   324/76.43
2   324/77.11
2   324/84
2   324/85
2   327/100
2   331/11
2   331/14
2   331/16
2   331/179
2   455/226.1
2   455/67.13
2   455/67.16
2   455/76
2   702/106
2   708/309
2   708/422
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Combined Classifications
```
7   324/613
5   324/76.23
5   324/76.27
3   331/2
3   331/25
3   342/145
2   324/622
2   324/76.17
2   324/76.19
2   324/76.26
2   324/76.29
2   324/76.43
2   324/77.11
2   324/84
2   324/85
2   327/100
2   327/105
2   331/11
2   331/14
2   331/16
2   331/179
2   331/19
2   342/135
2   342/192
2   455/226.1
2   455/67.13
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2  455/67.16
2  455/76
2  702/106
2  702/76
2  708/309
2  708/422
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Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10807205 on June 28, 2005


```
7   324/613       (7 OR, 0 XR)
        Class   324 :  ELECTRICITY:  MEASURING AND TESTING
        324/600        IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
                           REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
                           RELATIONSHIPS
        324/612        .Parameter related to the reproduction or
                           fidelity of a signal affected by a circuit under test
        324/613        ..Noise

5   324/76.23      (1 OR, 4 XR)
        Class   324 :  ELECTRICITY:  MEASURING AND TESTING
        324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                           SE
        324/76.12      .Analysis of complex waves
        324/76.19      ..Frequency spectrum analyzer
        324/76.23      ...With mixer

5   324/76.27      (2 OR, 3 XR)
        Class   324 :  ELECTRICITY:  MEASURING AND TESTING
        324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                           SE
        324/76.12      .Analysis of complex waves
        324/76.19      ..Frequency spectrum analyzer
        324/76.26      ...Scanning-panoramic receiver
        324/76.27      ....With particular sweep circuit

3   331/2          (2 OR, 1 XR)
        Class   331 :  OSCILLATORS
        331/1R         AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
                           OR FREQUENCY SENSING MEANS
        331/2          .Plural oscillators controlled

3   331/25         (0 OR, 3 XR)
        Class   331 :  OSCILLATORS
        331/1R         AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
                           OR FREQUENCY SENSING MEANS
        331/18         .With reference oscillator or source
        331/25         ..Signal or phase comparator

3   342/145        (0 OR, 3 XR)
        Class   342 :  COMMUNICATIONS:  DIRECTIVE RADIO WAVE SYSTEMS
                           AND DEVICES
        342/118        DETERMINING DISTANCE
        342/145        .With correlation

2   324/622        (0 OR, 2 XR)
        Class   324 :  ELECTRICITY:  MEASURING AND TESTING
        324/600        IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
                           REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
                           RELATIONSHIPS
        324/612        .Parameter related to the reproduction or
                           fidelity of a signal affected by a circuit under test
        324/620        ..Distortion
        324/622        ...Phase

2   324/76.17      (0 OR, 2 XR)
        Class   324 :  ELECTRICITY:  MEASURING AND TESTING
        324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                           SE
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         324/76.12      .Analysis of complex waves
         324/76.13      ..Amplitude distribution
         324/76.17      ...With integrator

2  324/76.19      (1 OR, 1 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.12      .Analysis of complex waves
         324/76.19      ..Frequency spectrum analyzer

2  324/76.26      (0 OR, 2 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.12      .Analysis of complex waves
         324/76.19      ..Frequency spectrum analyzer
         324/76.26      ...Scanning-panoramic receiver

2  324/76.29      (0 OR, 2 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.12      .Analysis of complex waves
         324/76.19      ..Frequency spectrum analyzer
         324/77.11      ...Nonscanning
         324/76.29      ....With filtering

2  324/76.43      (0 OR, 2 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.39      .Frequency of cyclic current or voltage (e.g.,
                          cyclic counting etc.)
         324/76.41      ..Frequency comparison, (e.g., heterodyne,
                          etc.)
         324/76.43      ...With plural mixers

2  324/77.11      (0 OR, 2 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.12      .Analysis of complex waves
         324/76.19      ..Frequency spectrum analyzer
         324/77.11      ...Nonscanning

2  324/84         (0 OR, 2 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.77      .Phase comparison (e.g., between cyclic pulse
                          voltage and sinusoidal current, etc.)
         324/84         ..With waveguide (e.g., coaxial cable)

2  324/85         (0 OR, 2 XR)
         Class  324 :  ELECTRICITY:  MEASURING AND TESTING
         324/76.11      MEASURING, TESTING, OR SENSING ELECTRICITY, PER
                          SE
         324/76.77      .Phase comparison (e.g., between cyclic pulse
                          voltage and sinusoidal current, etc.)
         324/85         ..With frequency conversion

2  327/100        (0 OR, 2 XR)
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        Class   327 :  MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
                          DEVICES, CIRCUITS, AND SYSTEMS
        327/100          SIGNAL CONVERTING, SHAPING, OR GENERATING

2  327/105        (1 OR, 1 XR)
        Class   327 :  MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
                          DEVICES, CIRCUITS, AND SYSTEMS
        327/100          SIGNAL CONVERTING, SHAPING, OR GENERATING
        327/105          .Synthesizer

2  331/11         (0 OR, 2 XR)
        Class   331 :  OSCILLATORS
        331/1R           AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
                            OR FREQUENCY SENSING MEANS
        331/10           .Plural A.F.S. for a single oscillator
        331/11           ..Plural comparators or discriminators

2  331/14         (0 OR, 2 XR)
        Class   331 :  OSCILLATORS
        331/1R           AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
                            OR FREQUENCY SENSING MEANS
        331/14           .With intermittent comparison controls

2  331/16         (0 OR, 2 XR)
        Class   331 :  OSCILLATORS
        331/1R           AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
                            OR FREQUENCY SENSING MEANS
        331/16           .Tuning compensation

2  331/179        (0 OR, 2 XR)
        Class   331 :  OSCILLATORS
        331/177R         WITH FREQUENCY ADJUSTING MEANS
        331/179          .Step-frequency change (e.g., band selection,
                            frequency-shift keying)

2  331/19         (1 OR, 1 XR)
        Class   331 :  OSCILLATORS
        331/1R           AUTOMATIC FREQUENCY STABILIZATION USING A PHASE
                            OR FREQUENCY SENSING MEANS
        331/18           .With reference oscillator or source
        331/19           ..Spectrum reference source

2  342/135        (2 OR, 0 XR)
        Class   342 :  COMMUNICATIONS:  DIRECTIVE RADIO WAVE SYSTEMS
                          AND DEVICES
        342/118          DETERMINING DISTANCE
        342/134          .With pulse modulation
        342/135          ..Digital (e.g., with counter)

2  342/192        (1 OR, 1 XR)
        Class   342 :  COMMUNICATIONS:  DIRECTIVE RADIO WAVE SYSTEMS
                          AND DEVICES
        342/175          WITH PARTICULAR CIRCUIT
        342/192          .Spectrum analysis

2  455/226.1      (0 OR, 2 XR)
        Class   455 :  TELECOMMUNICATIONS
        455/130          RECEIVER OR ANALOG MODULATED SIGNAL FREQUENCY
                            CONVERTER
        455/226.1        .Measuring or testing of receiver

2  455/67.13      (0 OR, 2 XR)
        Class   455 :  TELECOMMUNICATIONS
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```
      455/39          TRANSMITTER AND RECEIVER AT SEPARATE STATIONS

      455/67.11       .Having measuring, testing, or monitoring of
                        system or part
      455/67.13       ..Noise, distortion, or unwanted signal
                        detection (e.g., quality control, etc.)

2  455/67.16      (0 OR, 2 XR)
      Class    455 :  TELECOMMUNICATIONS
      455/39          TRANSMITTER AND RECEIVER AT SEPARATE STATIONS

      455/67.11       .Having measuring, testing, or monitoring of
                        system or part
      455/67.16       ..Phase measuring (e.g., group delay,
                        propagation effect, etc.)

2  455/76         (0 OR, 2 XR)
      Class    455 :  TELECOMMUNICATIONS
      455/73          TRANSMITTER AND RECEIVER AT SAME STATION (E.G.,
                        TRANSCEIVER)
      455/75          .With frequency stabilization (e.g., automatic
                        frequency control)
      455/76          ..Synthesizer

2  702/106        (0 OR, 2 XR)
      Class    702 :  DATA PROCESSING: MEASURING, CALIBRATING, OR
                        TESTING
      702/85          CALIBRATION OR CORRECTION SYSTEM
      702/106         .Signal frequency or phase correction

2  702/76         (1 OR, 1 XR)
      Class    702 :  DATA PROCESSING: MEASURING, CALIBRATING, OR
                        TESTING
      702/1           MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
      702/57          .Electrical signal parameter measurement system

      702/66          ..Waveform analysis
      702/75          ...Frequency
      702/76          ....Frequency spectrum

2  708/309        (0 OR, 2 XR)
      Class    708 :  ELECTRICAL COMPUTERS:  ARITHMETIC PROCESSING
                        AND CALCULATING
      708/100         ELECTRICAL DIGITAL CALCULATING COMPUTER
      708/200         .Particular function performed
      708/300         ..Filtering
      708/309         ...Frequency measurement

2  708/422        (0 OR, 2 XR)
      Class    708 :  ELECTRICAL COMPUTERS:  ARITHMETIC PROCESSING
                        AND CALCULATING
      708/100         ELECTRICAL DIGITAL CALCULATING COMPUTER
      708/200         .Particular function performed
      708/422         ..Correlation
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PLUS Search Results for S/N 10807205, Searched June 28, 2005

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